# International Rectifier

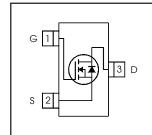
# IRLML2803PbF

- Generation V Technology
- Ultra Low On-Resistance
- N-Channel MOSFET
- SOT-23 Footprint
- Low Profile (<1.1mm)</li>
- Available in Tape and Reel
- Fast Switching
- Lead-Free
- · RoHS Compliant, Halogen-Free

## **Description**

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low onresistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

A customized leadframe has been incorporated into the standard SOT-23 package to produce a HEXFET Power MOSFET with the industry's smallest footprint. This package, dubbed the Micro3, is ideal for applications where printed circuit board space is at a premium. The low profile (<1.1mm) of the Micro3 allows it to fit easily into extremely thin application environments such as portable electronics and PCMCIA cards.







 $R_{DS(on)} = 0.25\Omega$ 



Base Part Number	Dookege Type	Standard F	Pack	Orderable Part Number	
base Part Number	Package Type	Form	Quantity Orderable Part Numb		
IRLML2803TRPbF	Micro3™ (SOT-23)	Tape and Reel	3000	IRLML2803TRPbF	

**Absolute Maximum Ratings** 

	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	1.2		
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	0.93	Α	
I <sub>DM</sub>	Pulsed Drain Current ①	7.3		
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation	540	mW	
	Linear Derating Factor	4.3	mW/°C	
$V_{GS}$	Gate-to-Source Voltage	±20	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy®	3.9	mJ	
dv/dt	Peak diode Recovery dv/dt <sup>②</sup>	5.0	V/ns	
$T_{J}$ , $T_{STG}$	Junction and Storage Temperature Range	-55 to + 150	°C	

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JA}$	Maximum Junction-to-Ambient ®		230	°C/W



## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

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	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	30			V	$V_{GS} = 0V, I_D = 250 \mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.029		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
В	Static Drain to Source On Registence			0.25		V <sub>GS</sub> = 10V, I <sub>D</sub> = 0.91A ③
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.40	Ω	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 0.46A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0			V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
9fs	Forward Transconductance	0.87			S	V <sub>DS</sub> = 10V, I <sub>D</sub> = 0.46A
I <sub>DSS</sub>	Drain-to-Source Leakage Current			1.0		V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V
IDSS	Brain-to-obtroe Leakage Garrent			25	μA	V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
lass	Gate-to-Source Forward Leakage			-100	nA	V <sub>GS</sub> = -20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			100	IIA	V <sub>GS</sub> = 20V
Qg	Total Gate Charge		3.3	5.0		I <sub>D</sub> = 0.91A
Q <sub>gs</sub>	Gate-to-Source Charge		0.48	0.72	nC	V <sub>DS</sub> = 24V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge		1.1	1.7		V <sub>GS</sub> = 10V, See Fig. 6 and 9 ③
t <sub>d(on)</sub>	Turn-On Delay Time		3.9			V <sub>DD</sub> = 15V
t <sub>r</sub>	Rise Time		4.0			$I_D = 0.91A$
t <sub>d(off)</sub>	Turn-Off Delay Time		9.0		ns	$R_G = 6.2\Omega$
t <sub>f</sub>	Fall Time		1.7			$R_D$ = 16 $\Omega$ , See Fig. 10 ③
C <sub>iss</sub>	Input Capacitance		85			V <sub>GS</sub> = 0V
Coss	Output Capacitance		34		pF	V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		15			f = 1.0MHz, See Fig. 5

# **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			0.54		MOSFET symbol
	(Body Diode)			0.54	Α	showing the
I <sub>SM</sub>	Pulsed Source Current			7.3		integral reverse
•	(Body Diode) ①			1.3		p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage			1.2	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 0.91A, V <sub>GS</sub> = 0V ③
t <sub>rr</sub>	Reverse Recovery Time		26	40	ns	$T_J = 25$ °C, $I_F = 0.91A$
Q <sub>rr</sub>	Reverse RecoveryCharge		22	32	nC	di/dt = 100A/µs ③

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- $@~I_{SD} \leq 0.91 A,~di/dt \leq 120 A/\mu s,~V_{DD} \leq V_{(BR)DSS},~T_{J} \leq 150 ^{\circ} C$
- 4 Surface mounted on FR-4 board,  $t \leq 5 sec.$
- $\ \, \ \,$  Limited by  $T_{Jmax},$  starting  $T_{J}=25^{\circ}C,\,L=9.4mH,\,R_{G}=25\Omega,\,I_{AS}=0.9A.$



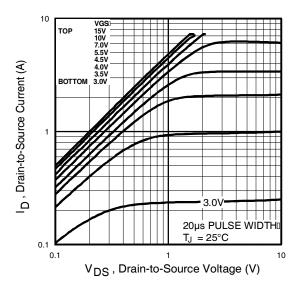


Fig 1. Typical Output Characteristics

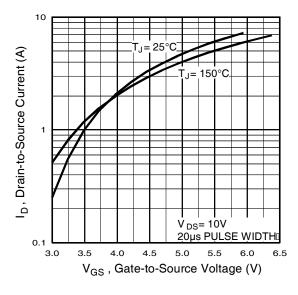


Fig 3. Typical Transfer Characteristics

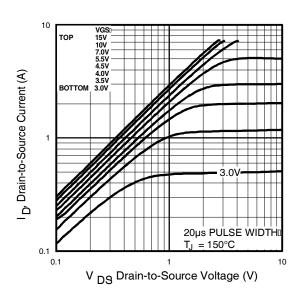
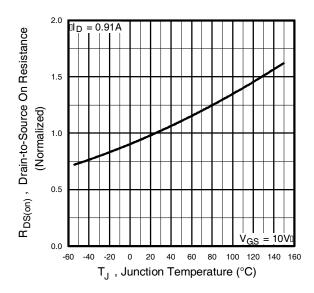
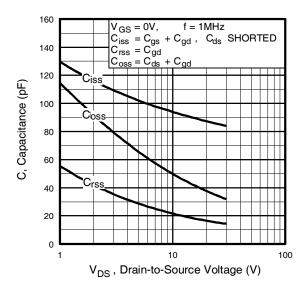


Fig 2. Typical Output Characteristics



**Fig 4.** Normalized On-Resistance Vs. Temperature





**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage

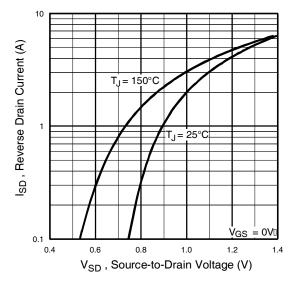
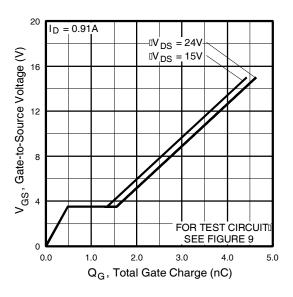


Fig 7. Typical Source-Drain Diode Forward Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

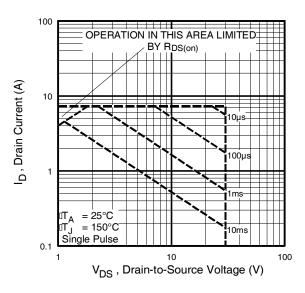


Fig 8. Maximum Safe Operating Area



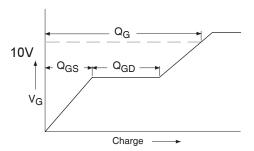


Fig 9a. Basic Gate Charge Waveform

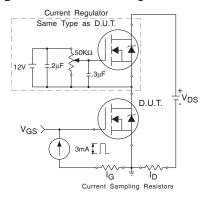


Fig 9b. Gate Charge Test Circuit

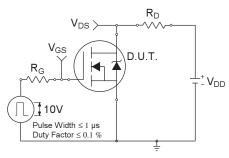


Fig 10a. Switching Time Test Circuit

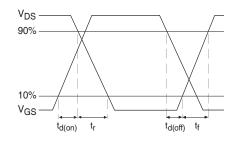


Fig 10b. Switching Time Waveforms

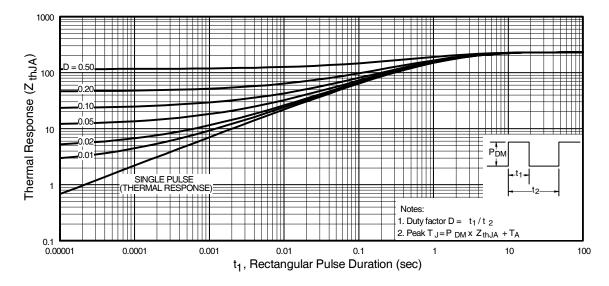


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient



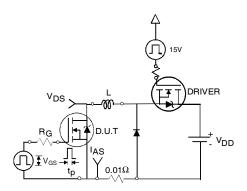


Fig 12a. Unclamped Inductive Test Circuit

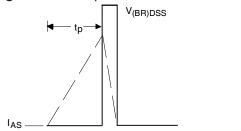
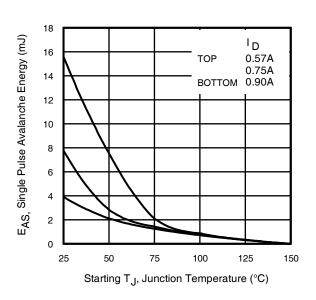
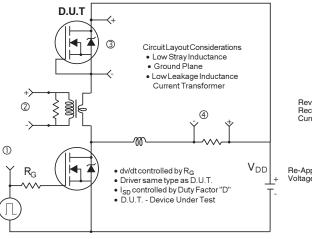
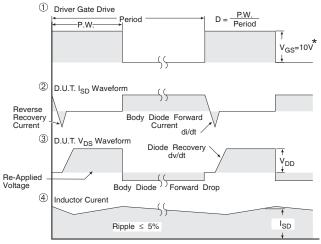


Fig 12b. Unclamped Inductive Waveforms



**Fig 12c.** Maximum Avalanche Energy vs. Drain Current





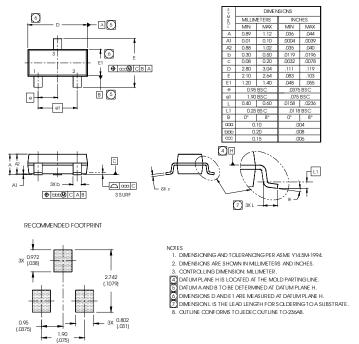
\*  $V_{GS}$  = 5V for Logic Level Devices

Fig 13. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs



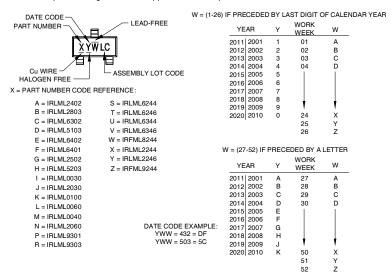
# Micro3 (SOT-23) (Lead-Free) Package Outline

Dimensions are shown in millimeters (inches)



# Micro3 (SOT-23 / TO-236AB) Part Marking Information

Notes: This part marking information applies to devices produced after 02/26/2001



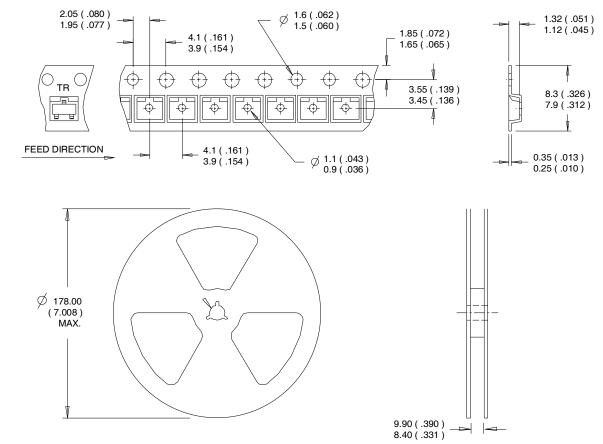
Note: For the most current drawing please refer to IR website at http://www.irf.com/package



# Tape & Reel Information

#### SOT-23

Dimensions are shown in millimeters (inches)



#### NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package

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### Qualification information<sup>†</sup>

Qualification level	Consumer (per JEDEC JESD47F <sup>††</sup> guidelines)			
Moisture Sensitivity Level	Micro3™ (SOT-23)	MSL1 (per JEDEC J-STD-020D <sup>††</sup> )		
RoHS compliant	Yes			

- † Qualification standards can be found at International Rectifier's web site: http://www.irf.com/product-info/reliability
- †† Applicable version of JEDEC standard at the time of product release

### **Revision History**

Date	Comment				
Updated data sheet with new IR corporate template.					
4/24/2014	Updated package outline & part marking on page 7.				
	Added Qualification table -Qual level "Consumer" on page 9.				
	Added bullet point in the Benefits "RoHS Compliant, Halogen -Free" on page 1.				



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